

RESISTIVE MEMORY DEVICE WITH A TREATED INTERFACE

Darrell Rinerson; Wayne Kinney; John Sanchez; Steven W. Longcor; Steve Kuo-Ren Hsia; Edmond R. Ward and Christophe J. Chevallier
Prepared by Beyer Weaver & Thomas, LLP, (650) 961-8300, Ref: UNTYP027; Contact Morgan Malino

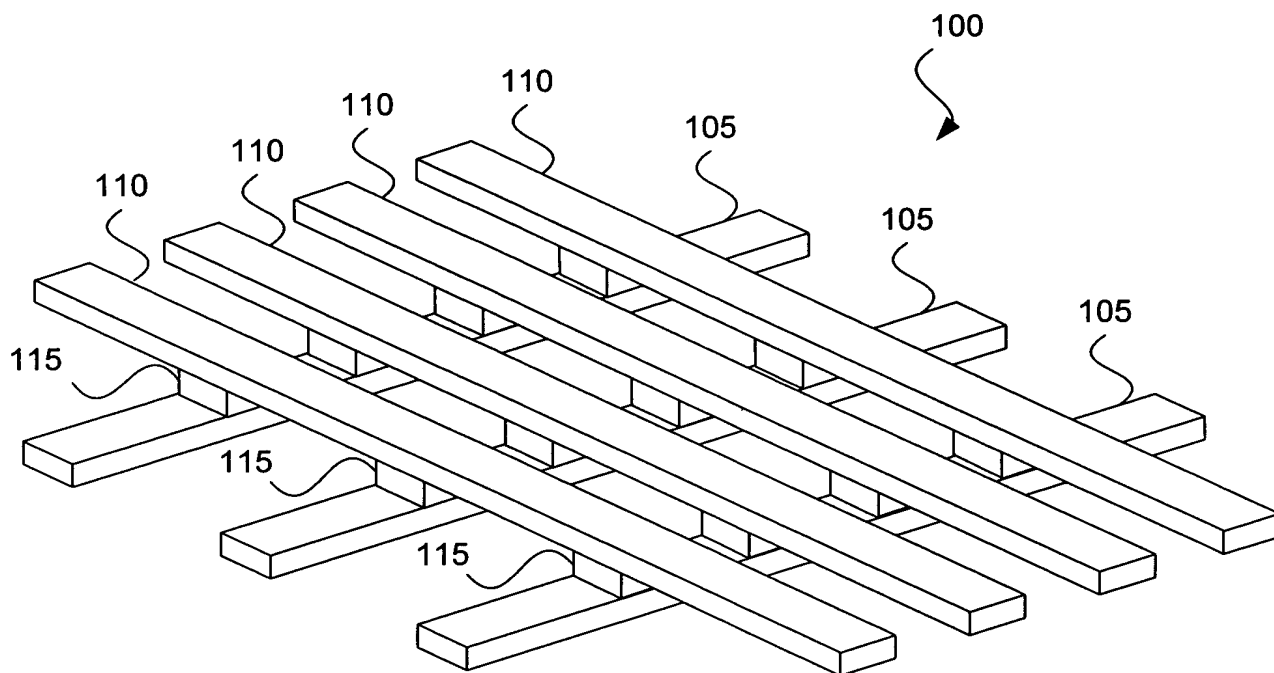


FIG. 1

RESISTIVE MEMORY DEVICE WITH A TREATED INTERFACE

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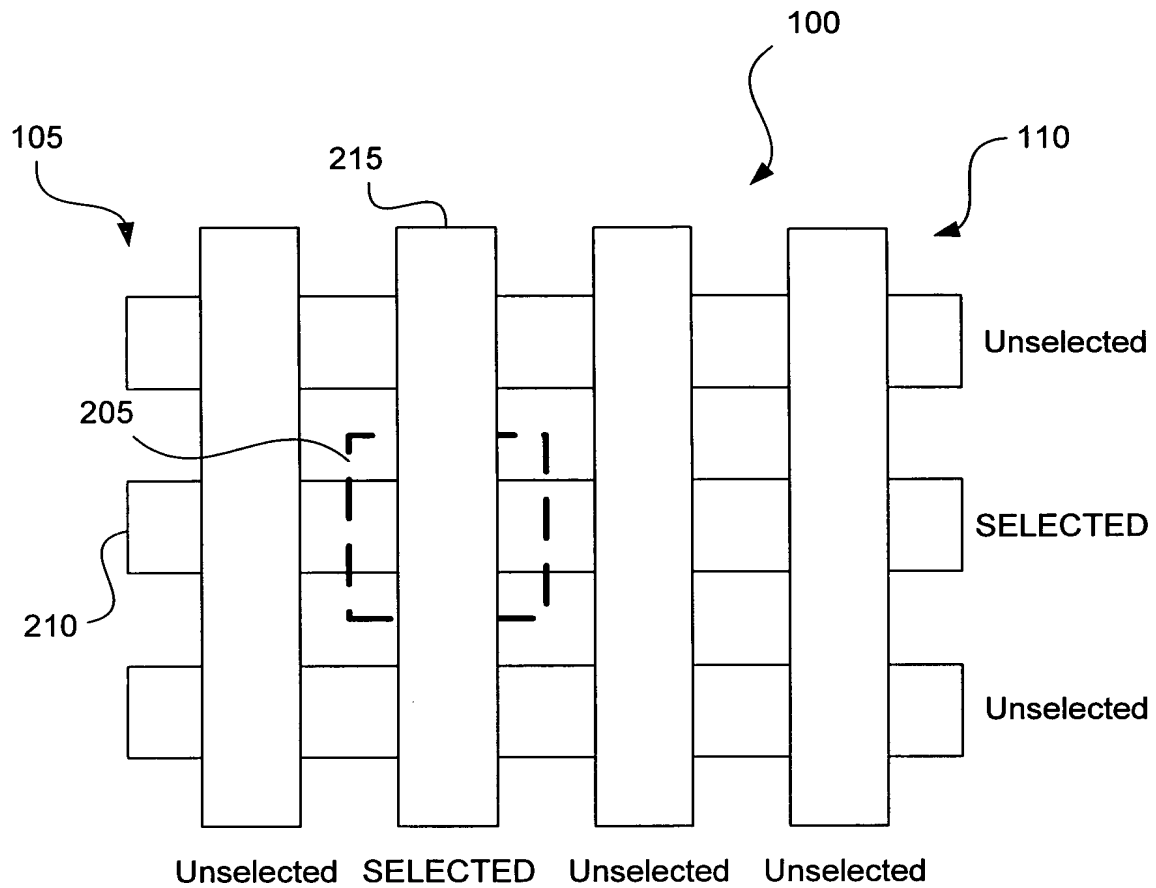


FIG. 2

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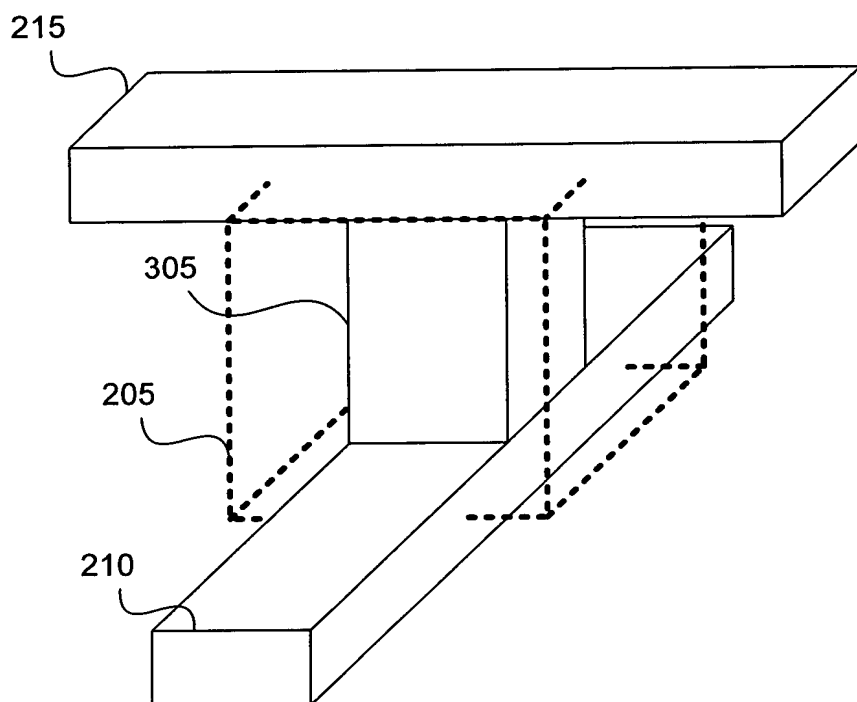


FIG. 3

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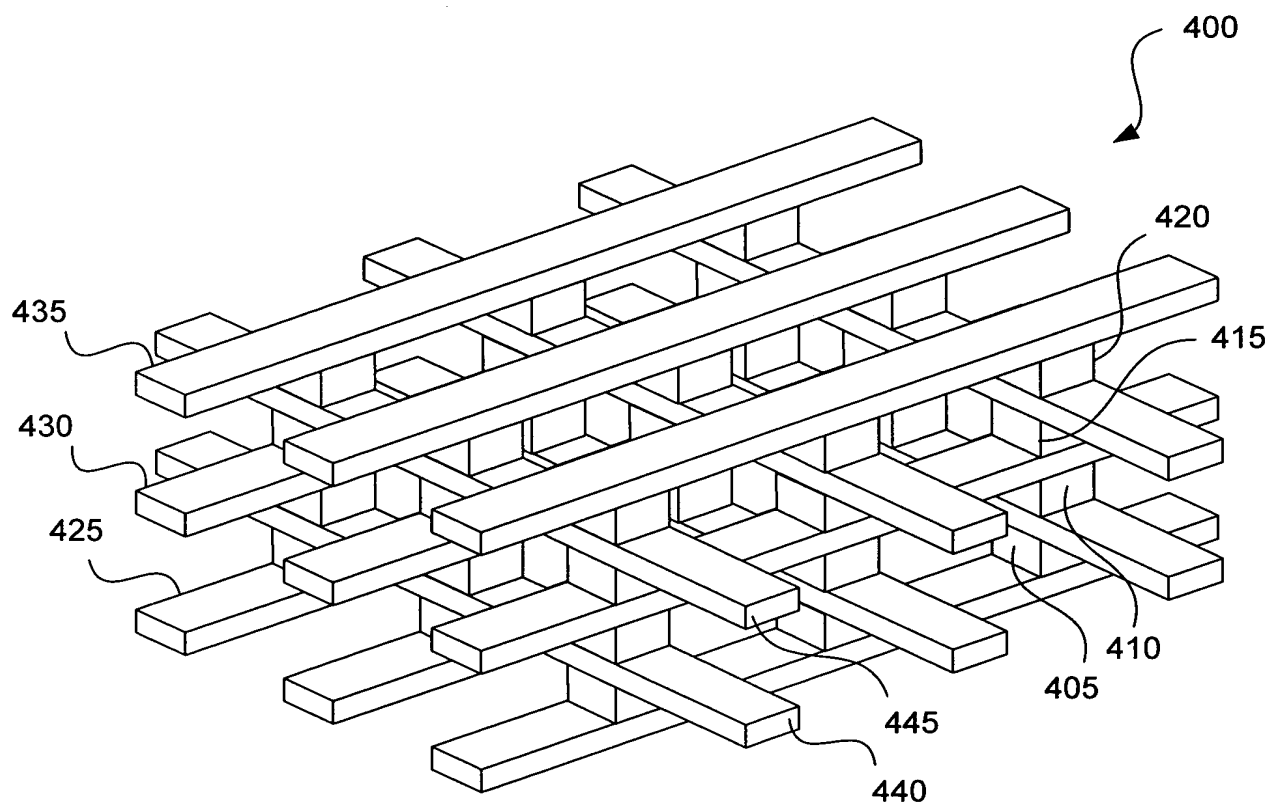


FIG. 4

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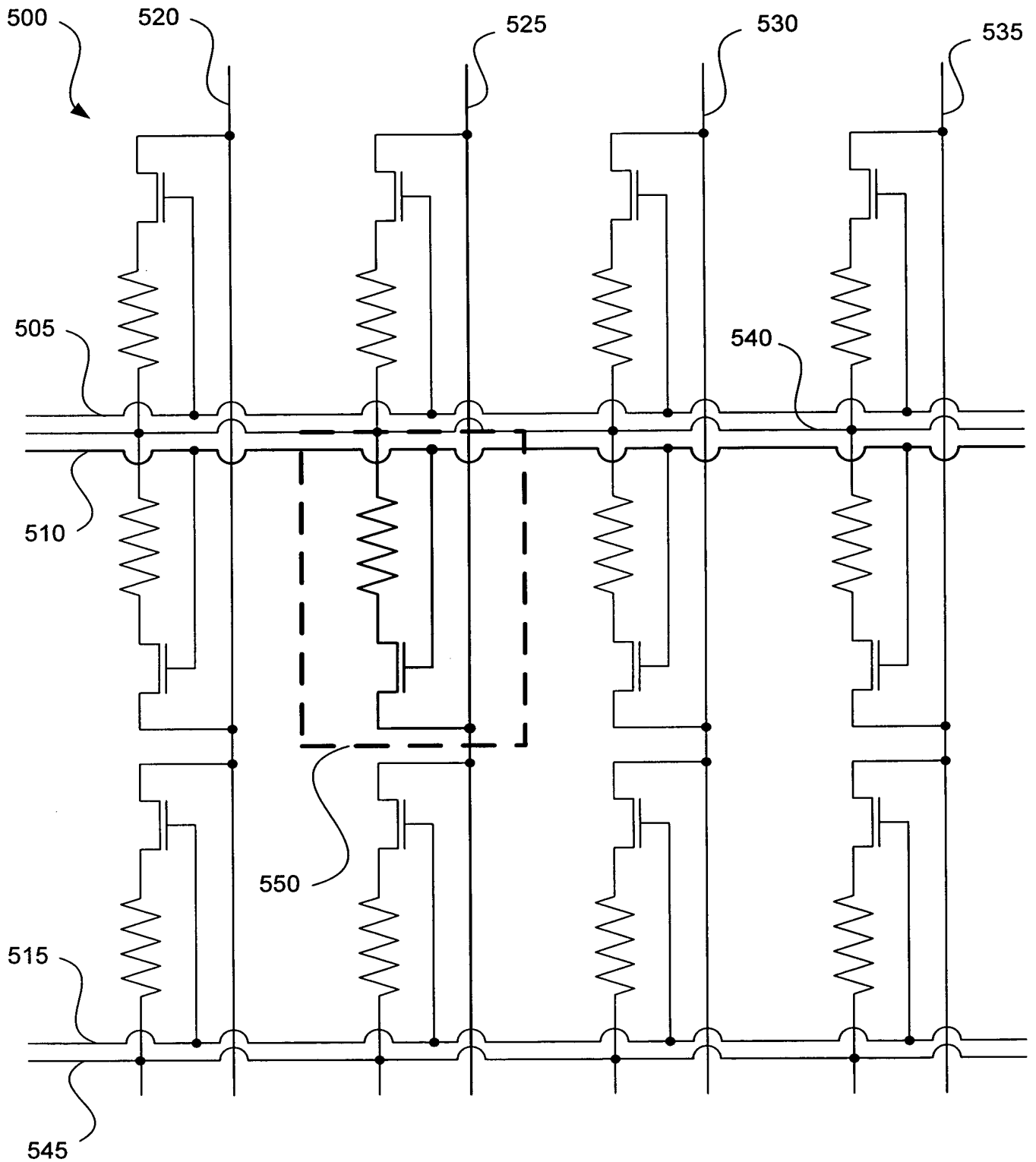


FIG. 5

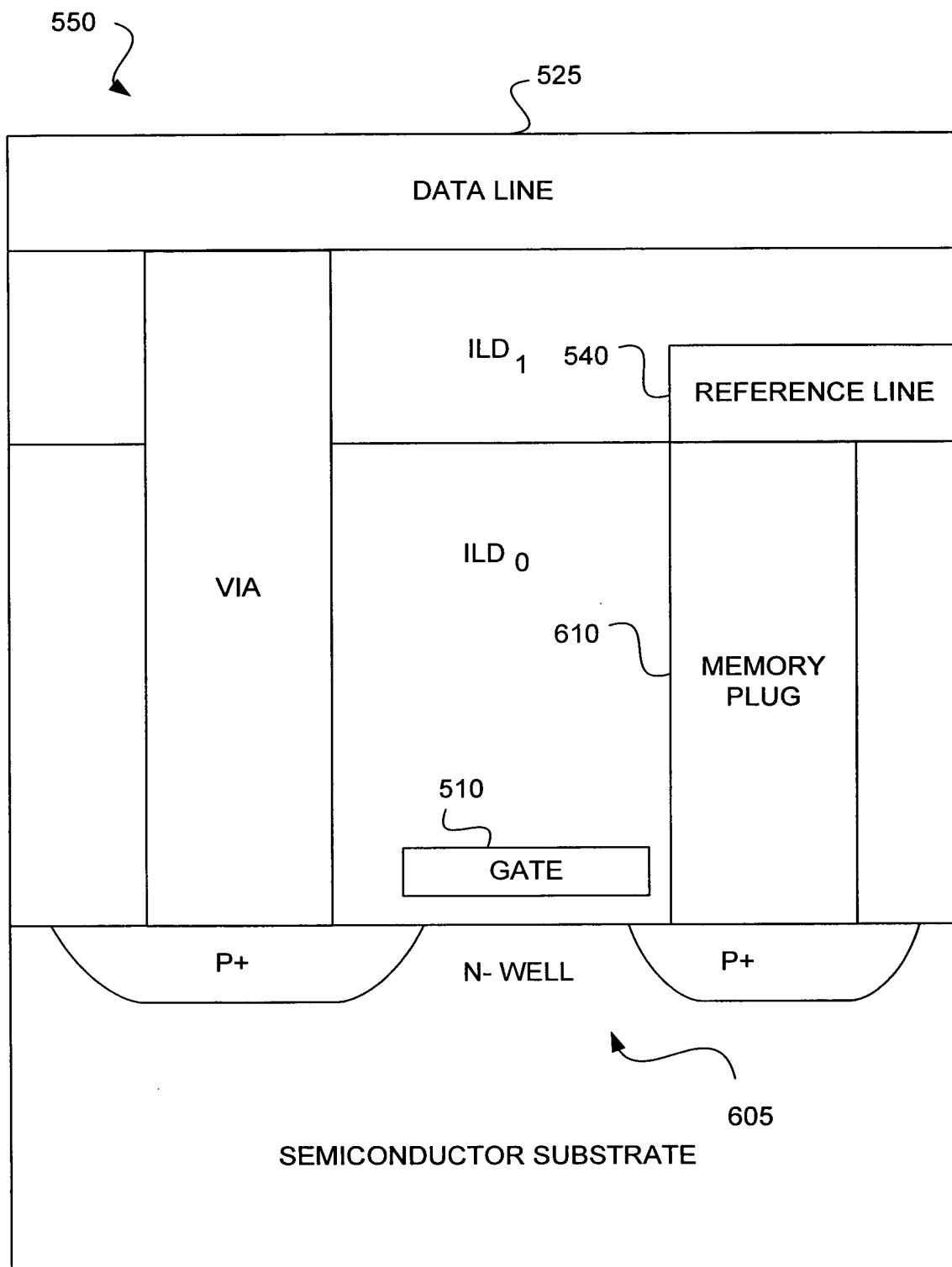


FIG. 6

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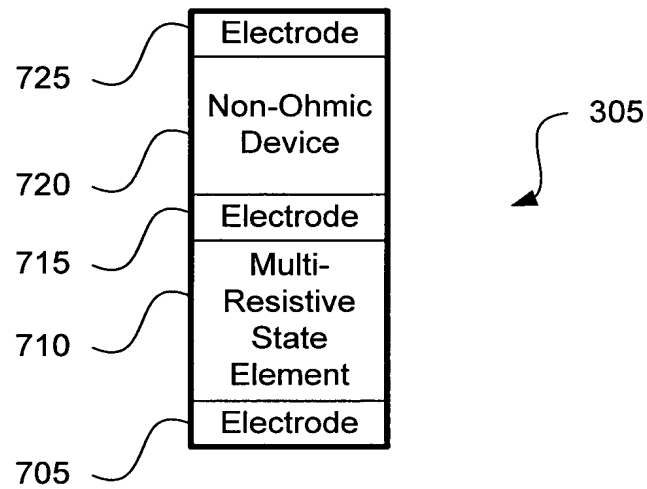


FIG. 7

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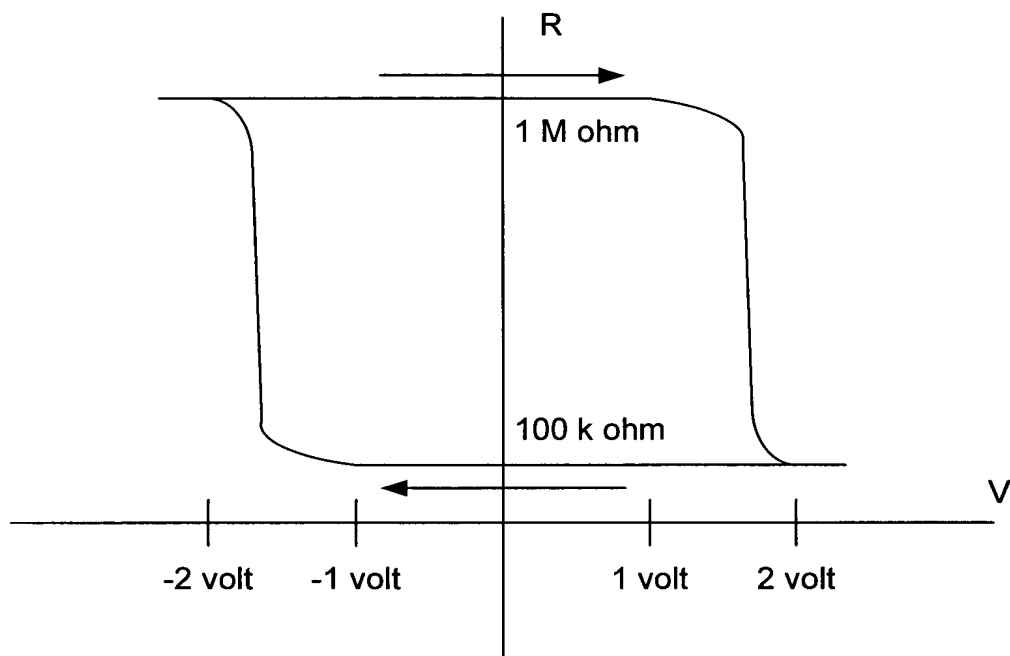


FIG. 8A

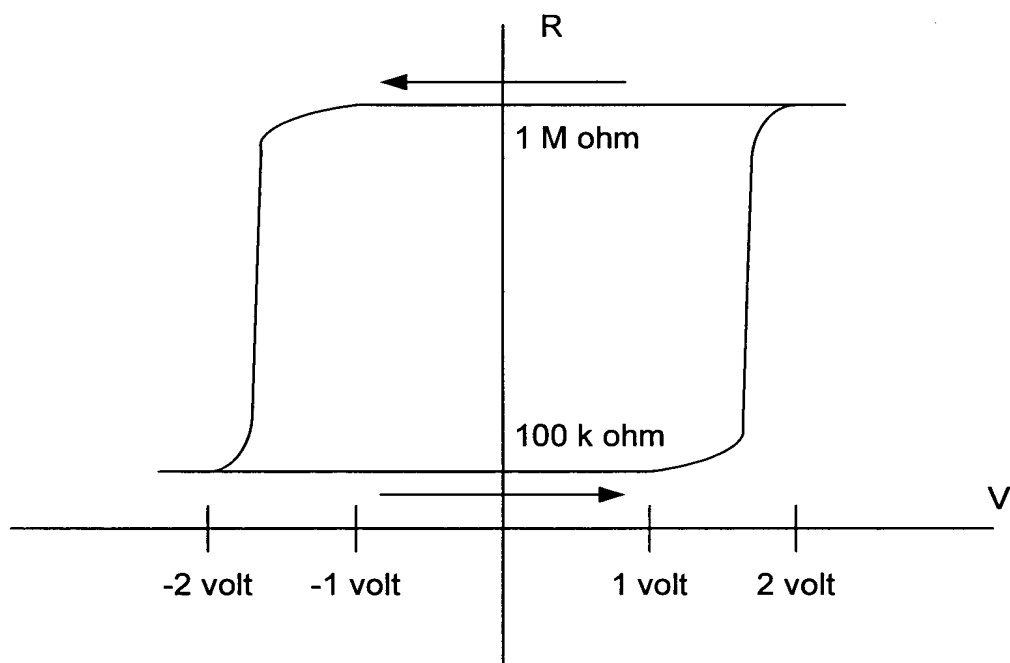


FIG. 8B

RESISTIVE MEMORY DEVICE WITH A TREATED INTERFACE

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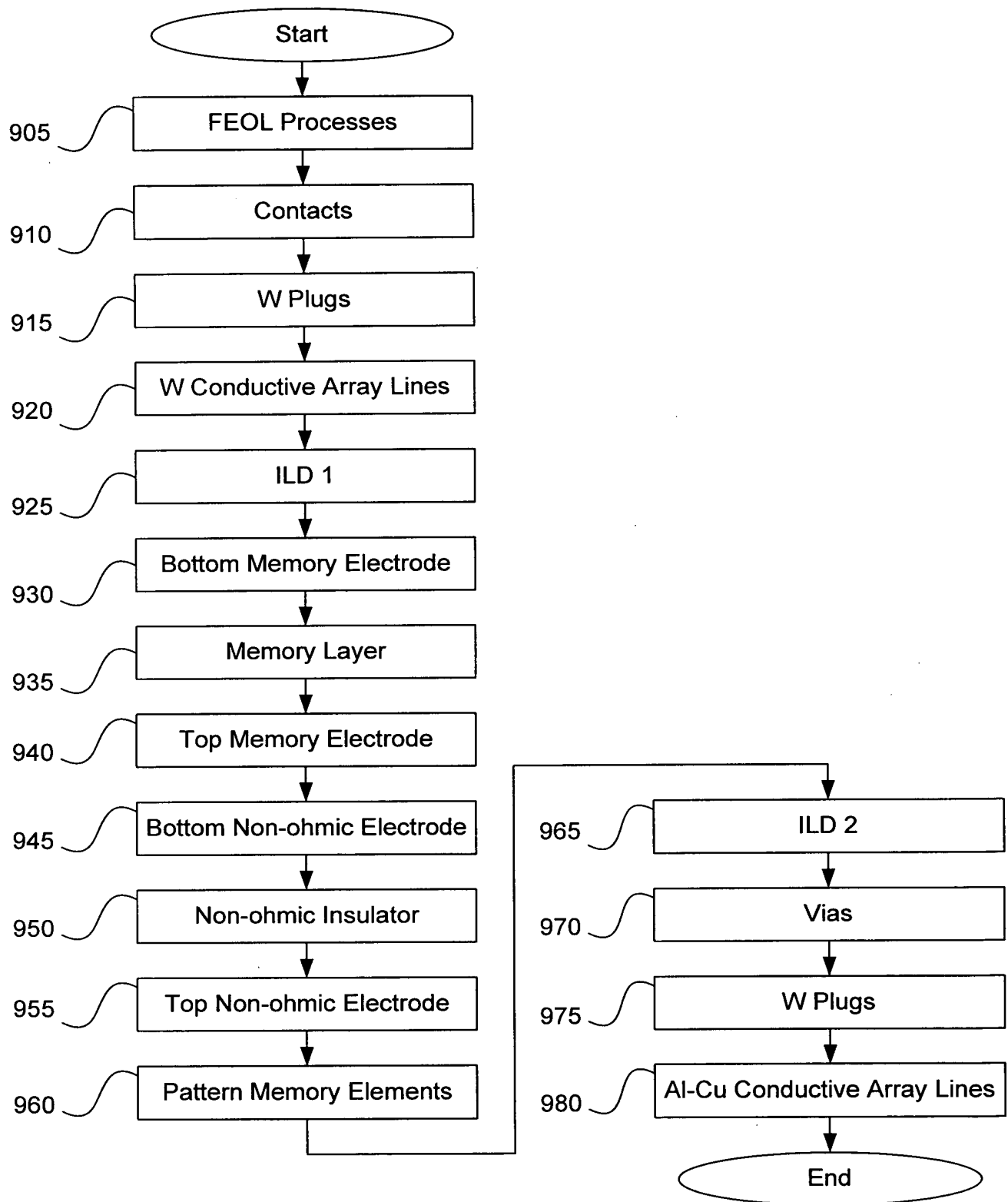


FIG. 9

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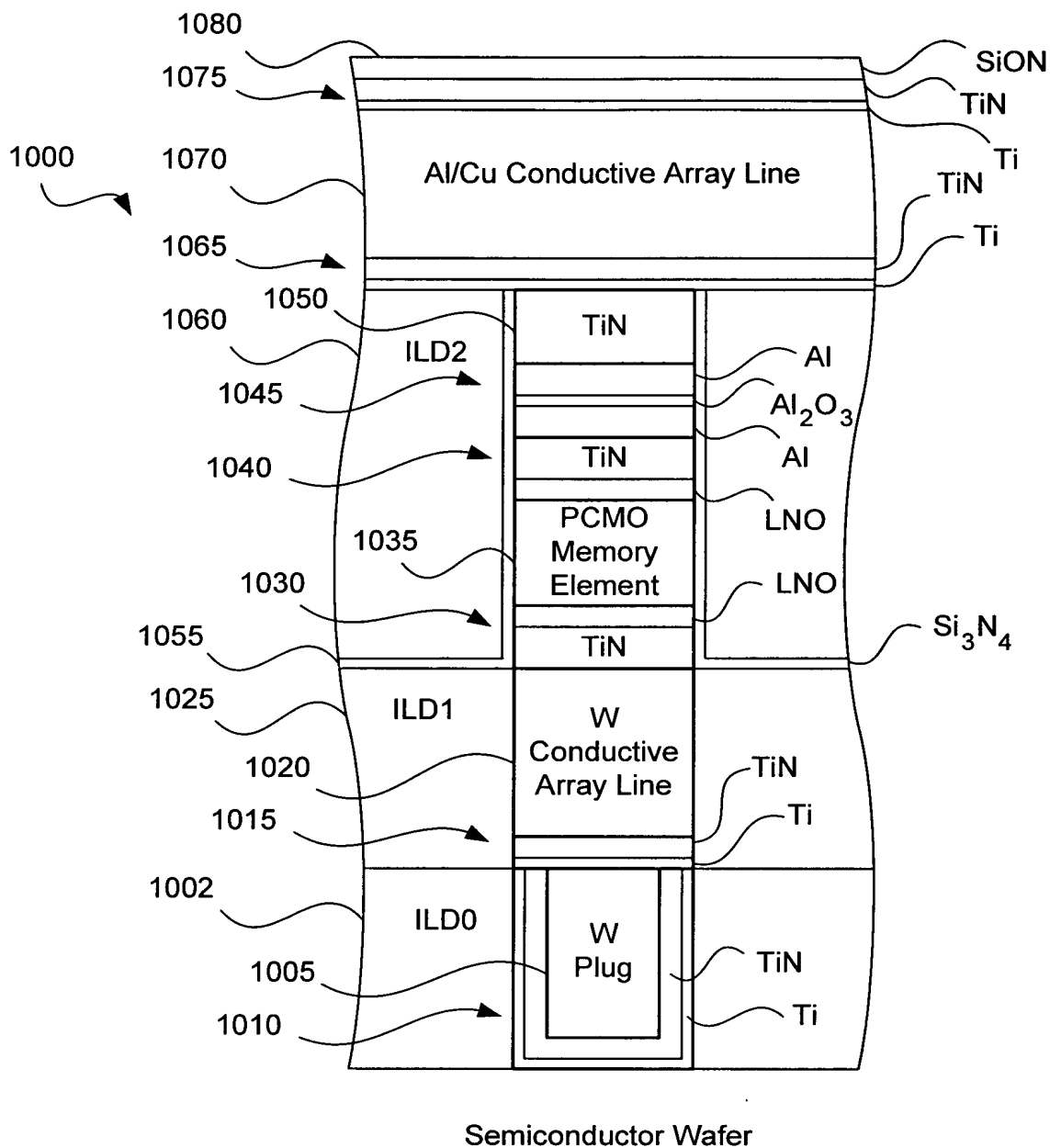


FIG. 10

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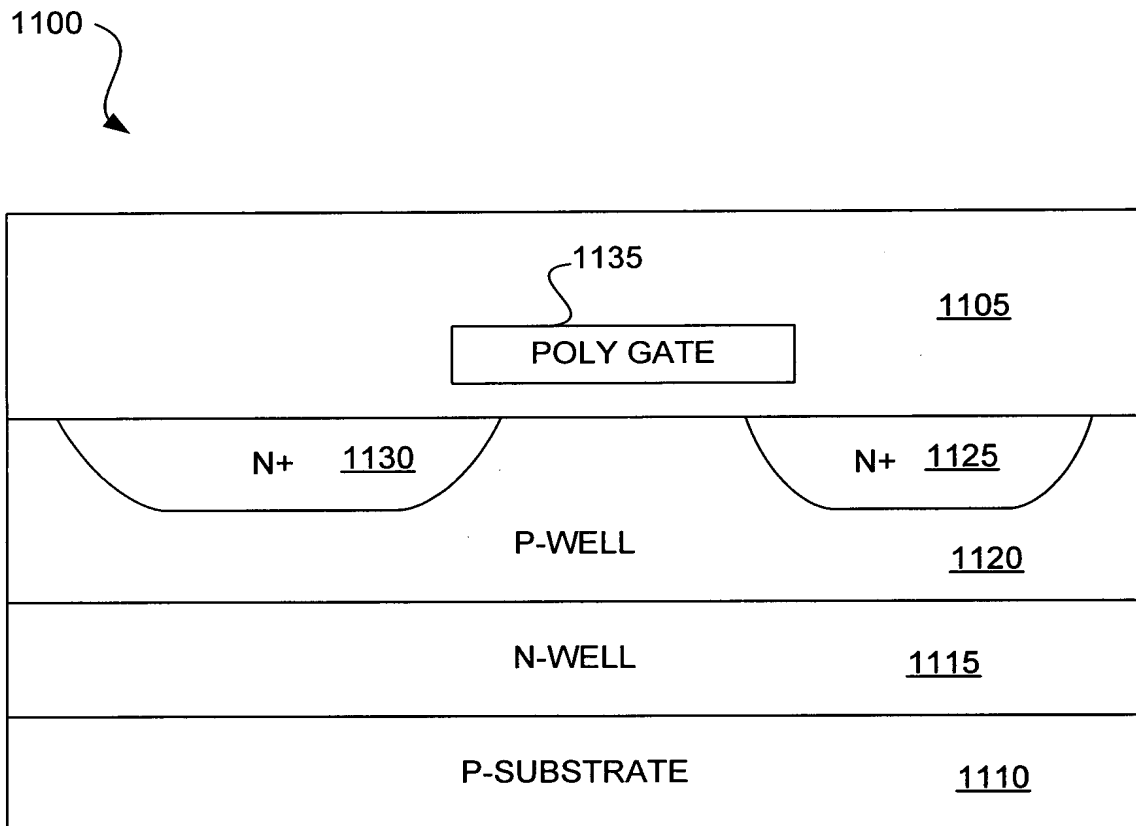


FIG. 11

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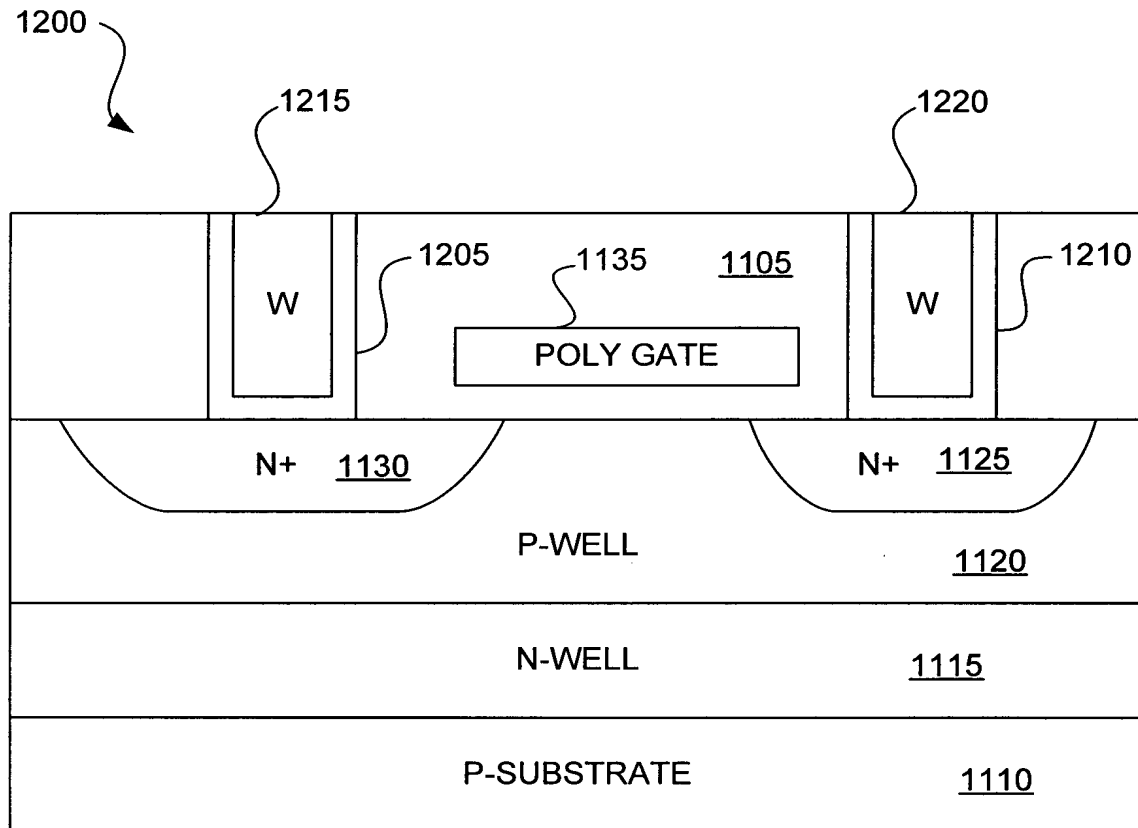


FIG. 12

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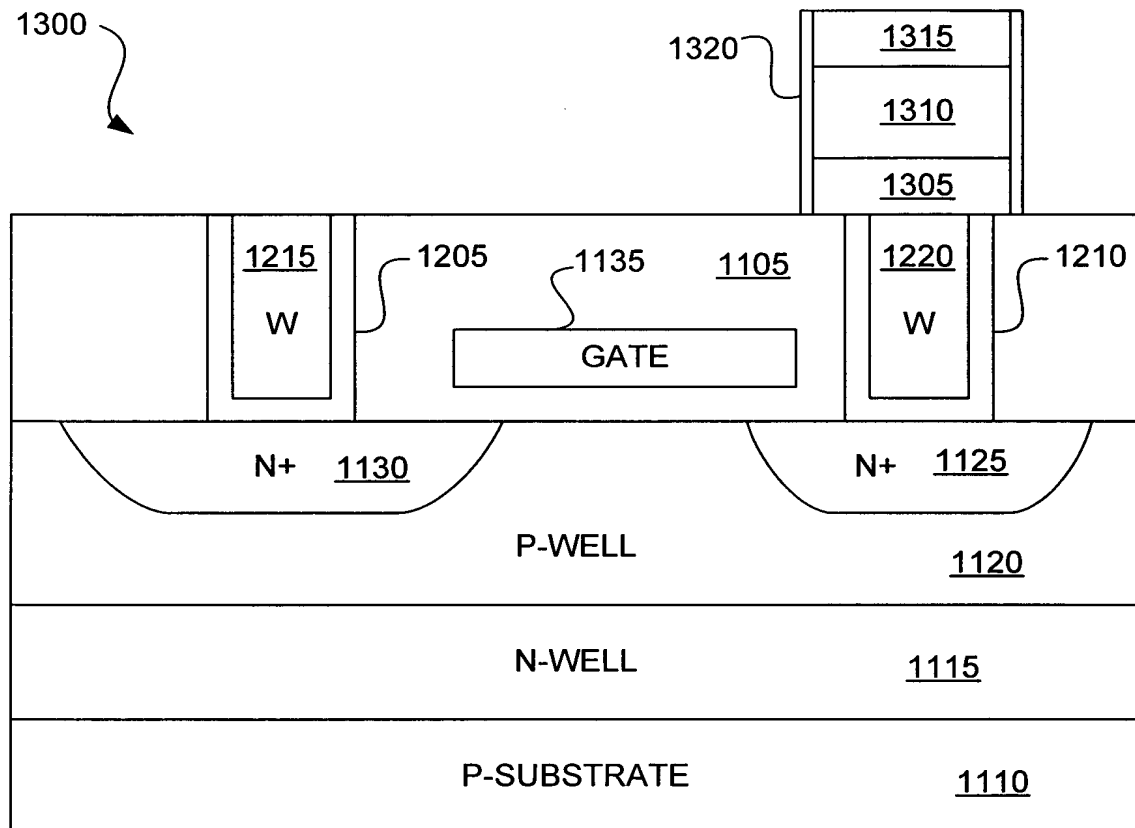


FIG. 13

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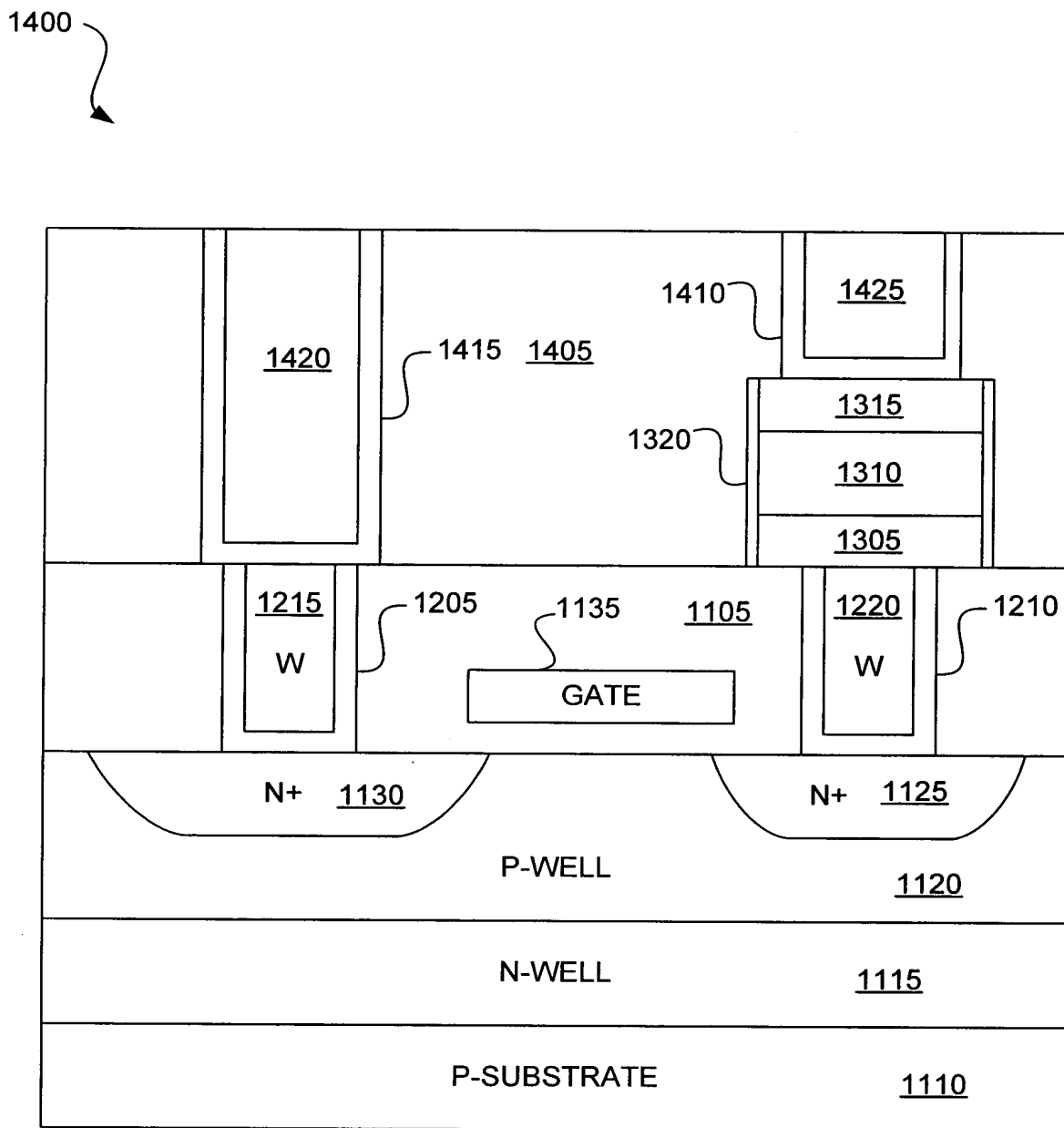


FIG. 14

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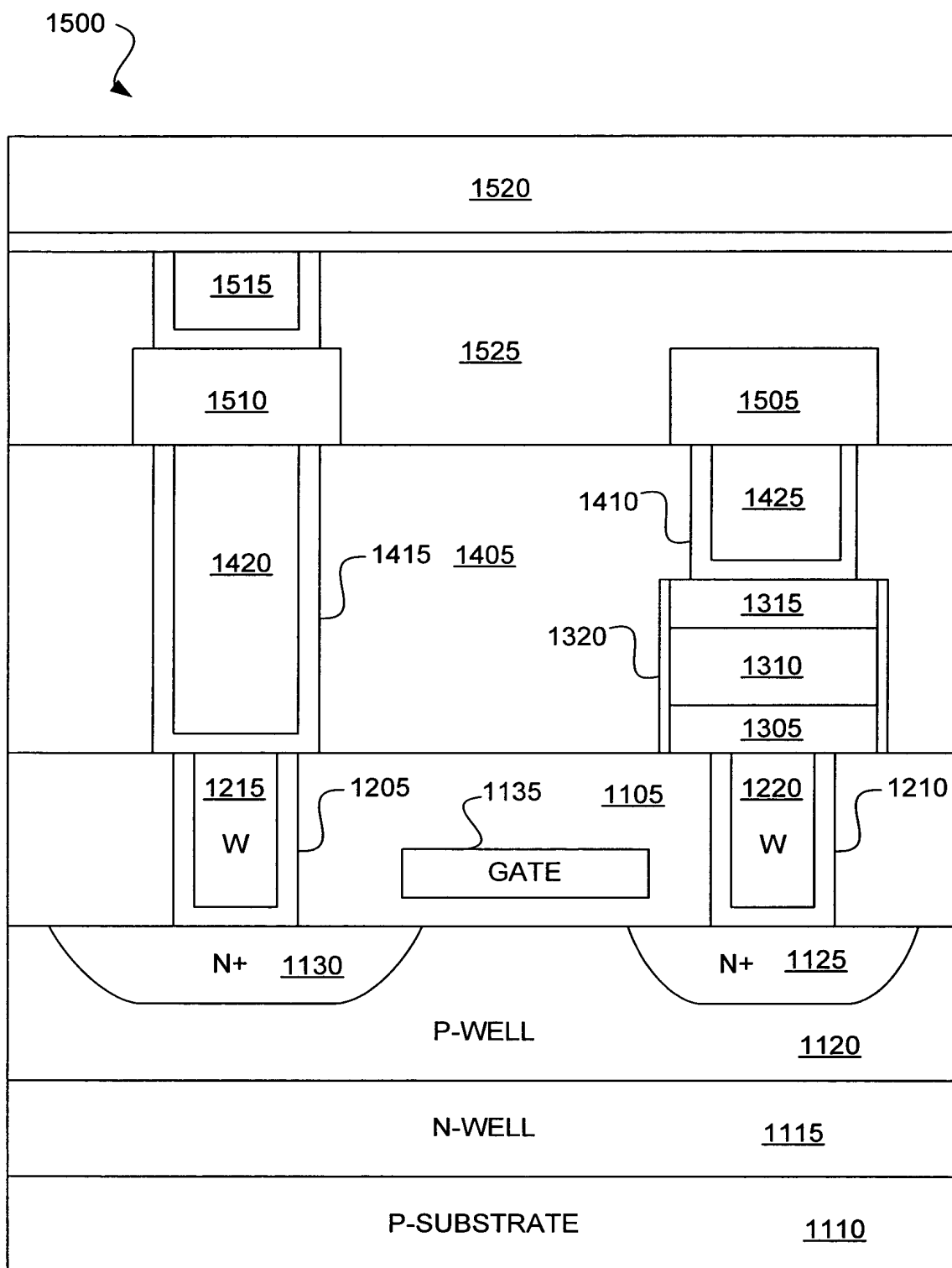


FIG. 15